

MSIN08

08:30 – Opening

09:00 – Daniel Resasco (U. of Oklahoma, USA)

Metrology of Single-walled Carbon Nanotube Products Manufactured in Large Scale

09:30 – Marc Hersam (Northwestern, USA)

Preparation and characterization of monodisperse carbon-based nanomaterials

10:00 – Kenji Hata (AIST, Japan)

“Super Growth”: Working to Supply the World with Catalyst-Free SWNTs

10:30 – Coffee break

10:50 – Lionel Le Bihan (Jobin Yvon, USA)

Carbon Nanotubes: What Information does Micro-Raman Spectroscopy bring?

11:20 – Bruce Weisman (Rice Univ. USA)

Qualitative and Quantitative Analysis of Bulk SWNT Samples using Near-IR Fluorimetry

11:50 – Thierry Michel (LCVN, U. Montpellier II, France)

Raman metrology of individual freestanding single-walled carbon nanotubes

12:30 – Lunch

13:40 – Simone Pokrant (Zeiss Company)

Advances in Electron Microscopy to determine the structure and the physical properties of CNTs

14:10 – Philippe Lambin (U. Namur, Belgique)

The use of electron diffraction for a precise determination of nanotube structure

14:40 – Paulo Bondavalli (Thales, France)

The use of nanotubes for gas detection and quantification: State-of-the-art and critical review

15:10 – Eleanor Campbell (Scotland)

The Use of Carbon Nanotubes for Developing Electromechanical Devices

15:40 – Coffee Break

16:00 – Peter Hatto (ISO, UK)

Standardization, characterization and metrology of nanotubes, the role of ISO TC 229

16:30 – Jeffrey Fagan (NIST, USA)

Carbon Nanotube Metrology and Reference Material Development at NIST

17:00 – Round table and closing at 18:00.